

# N-CHANNEL 600V - 0.098Ω - 40A ISOTOP PowerMesh™II MOSFET

TYPE	V <sub>DSS</sub>	R <sub>DS(on)</sub>	I <sub>D</sub>
STE40NC60	600V	< 0.13Ω	40 A

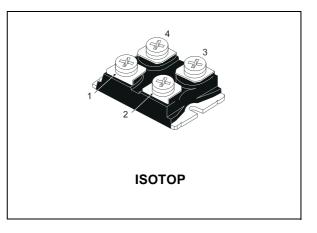
- TYPICAL  $R_{DS}(on) = 0.098 \Omega$
- EXTREMELY HIGH dv/dt CAPABILITY
   400% AV(ALANCUE TESTED
- 100% AVALANCHE TESTED
- NEW HIGH VOLTAGE BENCHMARK
- GATE CHARGE MINIMIZED

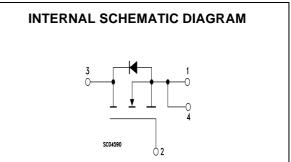
#### DESCRIPTION

The PowerMESH<sup>TM</sup>II is the evolution of the first generation of MESH OVERLAY<sup>TM</sup>. The layout refinements introduced greatly improve the Ron\*area figure of merit while keeping the device at the leading edge for what concerns swithing speed, gate charge and ruggedness.

#### **APPLICATIONS**

- HIGH CURRENT, HIGH SPEED SWITCHING
- SWITH MODE POWER SUPPLIES (SMPS)
- DC-AC CONVERTERS FOR WELDING EQUIPMENT AND UNINTERRUPTIBLE POWER SUPPLIES AND MOTOR DRIVER





#### **ABSOLUTE MAXIMUM RATINGS**

Symbol	Parameter	Value	Unit
V <sub>DS</sub>	Drain-source Voltage ( $V_{GS} = 0$ )	600	V
V <sub>DGR</sub>	Drain-gate Voltage ( $R_{GS} = 20 \text{ k}\Omega$ )	600	V
V <sub>GS</sub>	Gate- source Voltage	±30	V
Ι <sub>D</sub>	Drain Current (continuos) at T <sub>C</sub> = 25°C	40	Α
I <sub>D</sub>	Drain Current (continuos) at T <sub>C</sub> = 100°C	23	Α
I <sub>DM</sub> (•)	Drain Current (pulsed)	160	Α
P <sub>TOT</sub>	Total Dissipation at $T_C = 25^{\circ}C$	460	W
	Derating Factor	3.68	W/°C
dv/dt (1)	Peak Diode Recovery voltage slope	3	V/ns
VISO	Insulation Winthstand Voltage (AC-RMS)	2500	V
T <sub>stg</sub>	Storage Temperature	-65 to 150	°C
Tj	Max. Operating Junction Temperature	150	°C
)Pulse width li Iay 2002	mited by safe operating area	(1) I <sub>SD</sub> ≤ 40A, di/dt≤100 A/μs, V <sub>DD</sub> ≤ 24V, Tj≤T <sub>jMAX</sub>	1/8

#### THERMAL DATA

Rthj-case	Thermal Resistance Junction-case	Max	0.272	°C/W
Rthc-h	Thermal Resistance Case-heatsink with C Grease Applied	Conductive	0.05	°C/W

#### **AVALANCHE CHARACTERISTICS**

Symbol	Parameter	Max Value	Unit
I <sub>AR</sub>	Avalanche Current, Repetitive or Not-Repetitive (pulse width limited by $T_j$ max)	40	A
E <sub>AS</sub>	Single Pulse Avalanche Energy (starting $T_j = 25 \text{ °C}$ , $I_D = I_{AR}$ , $V_{DD} = 50 \text{ V}$ )	1150	mJ

# **ELECTRICAL CHARACTERISTICS** (TCASE = 25 °C UNLESS OTHERWISE SPECIFIED) OFF

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source Breakdown Voltage	I <sub>D</sub> = 250 μA, V <sub>GS</sub> = 0	600			V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current (V <sub>GS</sub> = 0)	$V_{DS}$ = Max Rating $V_{DS}$ = Max Rating, T <sub>C</sub> = 125 °C			10 100	μΑ μΑ
I <sub>GSS</sub>	Gate-body Leakage Current (V <sub>DS</sub> = 0)	$V_{GS} = \pm 30V$			±100	nA

### ON (1)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	2	3	4	V
R <sub>DS(on)</sub>	Static Drain-source On Resistance	V <sub>GS</sub> = 10V, I <sub>D</sub> = 20A		0.098	0.130	Ω

#### DYNAMIC

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
g <sub>fs</sub> (1)	Forward Transconductance	$V_{DS} > I_{D(on)} \times R_{DS(on)max,}$ $I_{D} = 15 \text{ A}$		42		S
Ciss	Input Capacitance	$V_{DS} = 25V, f = 1 \text{ MHz}, V_{GS} = 0$		11.1		nF
Coss	Output Capacitance			1190		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			100		pF

Note: 1. Pulsed: Pulse duration =  $300 \ \mu$ s, duty cycle 1.5 %.

# ELECTRICAL CHARACTERISTICS (CONTINUED)

# SWITCHING ON

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t <sub>d(on)</sub>	Turn-on Delay Time	$V_{DD} = 300 \text{ V}, I_D = 20 \text{ A}$		49		ns
tr	Rise Time	$R_G = 4.7\Omega V_{GS} = 10V$ (see test circuit, Figure 3)		42		ns
Qg	Total Gate Charge	$V_{DD} = 480V, I_D = 40A,$		307.5	430	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 10V		48		nC
Q <sub>gd</sub>	Gate-Drain Charge			146.5		nC

#### SWITCHING OFF

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
t <sub>r(Voff)</sub>	Off-voltage Rise Time	$V_{DD} = 480V, I_D = 40A,$		41		ns
t <sub>f</sub>	Fall Time	$R_G = 4.7\Omega, V_{GS} = 10V$ (see test circuit, Figure 5)		26		ns
t <sub>c</sub>	Cross-over Time			74		ns

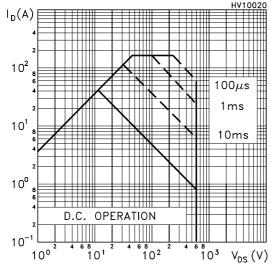
#### SOURCE DRAIN DIODE

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub>	Source-drain Current				40	А
I <sub>SDM</sub> (2)	Source-drain Current (pulsed)				160	А
V <sub>SD</sub> (1)	Forward On Voltage	$I_{SD} = 40A, V_{GS} = 0$			1.6	V
t <sub>rr</sub>	Reverse Recovery Time	I <sub>SD</sub> = 40 A, di/dt = 100 A/µs,		685		ns
Qrr	Reverse Recovery Charge	V <sub>DD</sub> = 40 V, T <sub>j</sub> = 150 °C (see test circuit, Figure 5)		15		μC
I <sub>RRM</sub>	Reverse Recovery Current			44		А

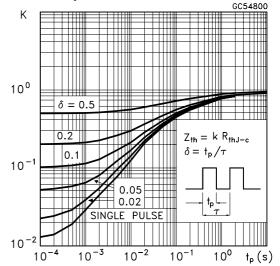
 Note:
 1. Pulsed: Pulse duration = 300 μs, duty cycle 1.5 %.

 2. Pulse width limited by safe operating area.

### Safe Operating Area

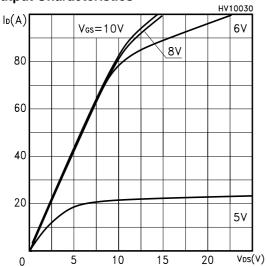


#### **Thermal Impedence**

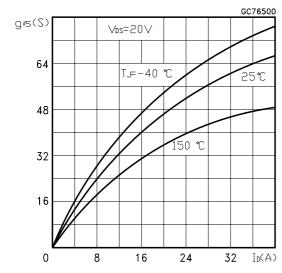


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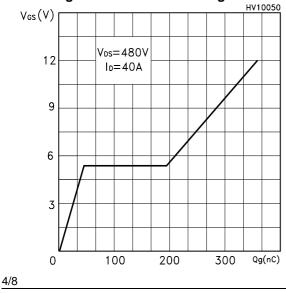
# **Output Characteristics**



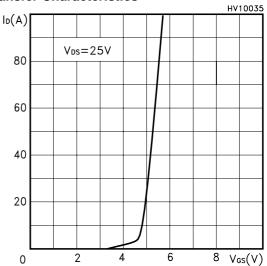
#### Transconductance



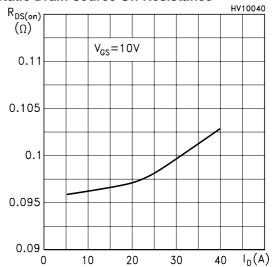
Gate Charge vs Gate-source Voltage

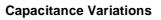


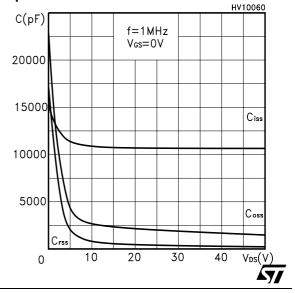
Transfer Characteristics

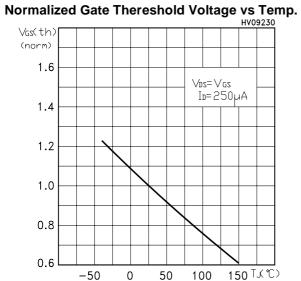


Static Drain-source On Resistance

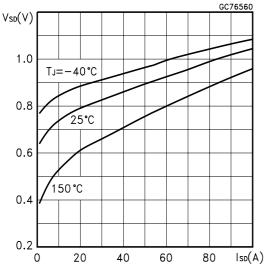






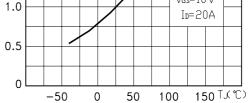


**Source-drain Diode Forward Characteristics** 



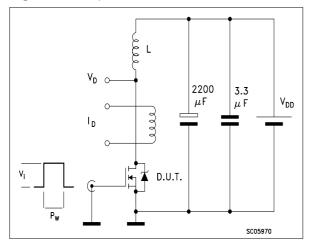
Ros(on) (norm) 2.5 2.0 1.5 VGs=10∨ 1.0

Normalized On Resistance vs Temperature

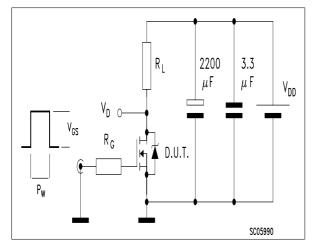


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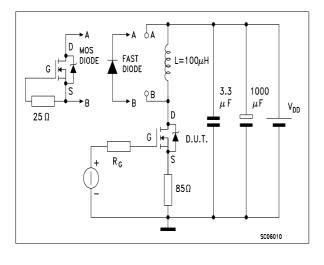
Fig. 1: Unclamped Inductive Load Test Circuit



**Fig. 3:** Switching Times Test Circuit For Resistive Load



**Fig. 5:** Test Circuit For Inductive Load Switching And Diode Recovery Times



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#### Fig. 2: Unclamped Inductive Waveform

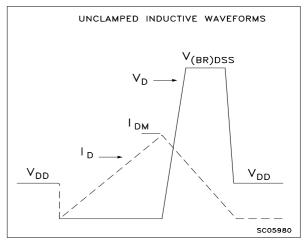
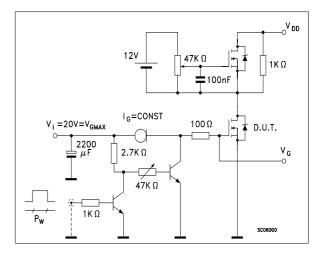


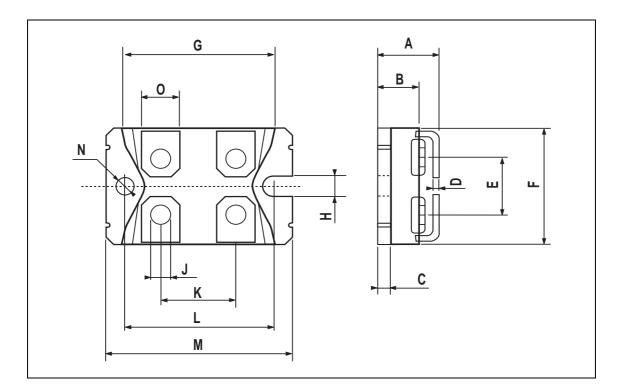
Fig. 4: Gate Charge test Circuit





DIM.		mm		inch			
Diwi.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.	
А	11.8		12.2	0.466		0.480	
В	8.9		9.1	0.350		0.358	
С	1.95		2.05	0.076		0.080	
D	0.75		0.85	0.029		0.033	
E	12.6		12.8	0.496		0.503	
F	25.15		25.5	0.990		1.003	
G	31.5		31.7	1.240		1.248	
Н	4			0.157			
J	4.1		4.3	0.161		0.169	
К	14.9		15.1	0.586		0.594	
L	30.1		30.3	1.185		1.193	
М	37.8		38.2	1.488		1.503	
Ν	4			0.157			
0	7.8		8.2	0.307		0.322	

### **ISOTOP MECHANICAL DATA**



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